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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Rajski et al.
Application No. 09/620,021
Filed: July 20, 2000
Confirmation No. 3823
For: CONTINUOUS APPLICATION AND DECOMPRESSION OF TEST PATTERNS TO A CIRCUIT-UNDER-TEST
Examiner: Phung M. Chung
Art Unit: 2133
Attorney Reference No. 1011-54375-01

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Attorney or Agent for Applicants _____

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Respectfully submitted,

KLARQUIST SPARKMAN, LLP

By _____
Patrick M. Bible
Registration No. 44,423

One World Trade Center, Suite 1600
121 S.W. Salmon Street
Portland, Oregon 97204
Telephone: (503) 226-7391
Facsimile: (503) 228-9446

cc: Client
Docketing

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Attorney Docket Number	1011-54375-01
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Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	2133
Examiner Name	Phung M. Chung

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U.S. PATENT DOCUMENTS

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Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
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FOREIGN PATENT DOCUMENTS

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Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
		Aitken et al., "A Diagnosis Method Using Pseudo-Random Vectors Without Intermediate Signatures," *Proc. ICCAD*, pp. 574-577 (1989).
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		Benowitz et al., "An Advanced Fault Isolation System for Digital Logic," *IEEE Transactions on Computers*, Vol. C-24, No. 5, pp. 489-497 (May 1975).
		Chakrabarty et al., "Optimal Zero-Aliasing Space Compaction of Test Responses," *IEEE Transactions on Computers*, Vol. 47, No. 11, pp. 1171-1187 (November 1998).
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		Ghosh-Dastidar et al., "Fault Diagnosis in Scan-Based BIST Using Both Time and Space Information," *Proc. ITC*, pp. 95-102 (September 1999).
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		Wu et al., "Scan-Based BIST Fault Diagnosis," *IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems*, Vol. 18, No. 2, pp. 203-211 (February 1999).

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